

1. Scope

This specification is applied to Multilayer Ceramic Chip Capacitor (MLCC) for use in electric equipment for the voltage is ranging from 100V to 1.5 KV (not Include).

The MLCC support for Lead-Free wave and reflow soldering, and electrical characteristic and reliability are same as before. (This product is compliant with the RoHS & HF.)

2. Parts Number Code

	C 1210	X	683	к	631] _т_]	F	F
	(1) (2)	(3)	(4)	(5)	(6)	(7)	(8)	(9)
(1)Product				(5)Ca	pacitan	ce Tolerance	e	
Product Co	de			Code	э.	Tolerance	Nomin	al Capacitance
С	Multilaye	r Ceramic Ch	ip Capacitor	K	:	± 10.0 %	More	e Than 10 pF
(2)Chip Siz	ze			(6) R a	ted Volt	age		
Code	Length×Width	unit : mm	n(inch)	Code	9	Rate	d Voltage (V	dc)
1210	3.20× 2	2.50 (.126×	.098)	631			630	
Code Temp	•	rature Te	mperature	(7)Ta Code	pping e		Туре	
	acteristic Rar	0	Coefficient	_ <u>T</u>		Та	ape & Reel	
X X (4)Capacita	<mark>(7R -55℃~-</mark> ance		co farads(pF)	- (8)Th - Cod	ickness	Thio	kness T (m	m
Code	Nominal (Capacitance (p	F)	– <u>COU</u>	e		2.00± 0.20	111)
	s a decimal point,	68,000.0 it shall be expr	ressed by an		ecial Co			
English c	capital letter R			Code	e		Туре	
3. Nominal	Capacitance an	d Tolerance		F		Sp	becial Code	e
	ard Combinatio		I Capacitan	ce and Tol	erance			
Class	Characteristic		Tolerance)		Nomin	al Capacita	nce
Class	Characteristic		Telefallee					

3.2 E series(standard Number)

Standard No.		Application Capacitance										
E- 3		1.0				2.2			4.7			
E- 6	1.0		1	.5	2	.2	3	.3	4	.7	6	.8
E-12	1.0	1.2	1.5	1.8	2.2	2.7	3.3	3.9	4.7	5.6	6.8	8.2
E-24	1.0	1.2	1.5	1.8	2.2	2.7	3.3	3.9	4.7	5.6	6.8	8.2
	1.1	1.3	1.6	2.0	2.4	3.0	3.6	4.3	5.1	6.2	7.5	9.1

4. Operation Temperature Range

Class	Characteristic	Temperature Range	Reference Temp.
Π	X7R	-55℃ ~ +125℃	25℃

5. Storage Condition

Storage Temperature : 5 to 40 $^\circ\mathrm{C}$

Relative Humidity : 20 to 70 %

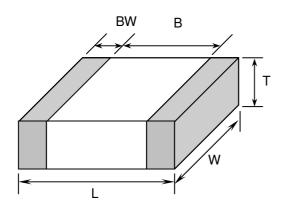
Storage Time: 12 months max.





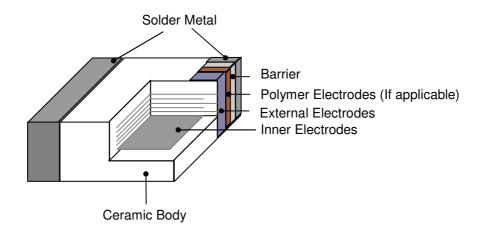
6. Dimensions

6.1 Configuration and Dimension :



					Unit:mm
TYPE	L	W	Т	B (min)	BW (min)
1210	3.20± 0.30	2.50±0.20	2.00±0.20	1.60	0.30

6.2 Termination Type :







7. Performance

No.	ltem		S	pecification	Test Condition
1	Visua	ıl	No abnormal	exterior appearance	Visual inspection
2	Dimens	ion	See Page 2		Visual inspection
3	Insulati Resista		500/CΩmin.		V>500V, Applied 500Vdc Charge Time : 60sec. Is applied less than 50mA current.
4	Capacitance	Class ∏	Within The Sp	ecified Tolerance	Class II :FrequencyVoltageX7R1KHz $\pm 10\%$ 1.0 ± 0.2 VrmsPerform a heat temperature at 150 $\pm 5^{\circ}$ C for 30min. then place room temp. for 24 ± 2 hr.
5	D.F.	Class ∏	Char. X7R:2.5% m	Maximum ax.	
6	Withstan Voltag	-	No dielectric mechanical b	breakdown or reakdown	 500V≦V<1000V: 150% Rated Voltage Voltage ramp up rate≦500v/sec for 1~5 sec. charge/discharge Current is less than 50mA. ※ Withstanding voltage testing requires immersion of the element in a isolation fluid prevent arcing on the chip surface, at voltage over 1000Vdc.
7	Temperature Capacitance Coefficient	Class ∏	Char. Temp. F X7R -55℃~₁		Class II : (C2-C1)/C1 × 100% C1:Capacitance at standard temperature(25℃) C2: Capacitance at test temperature (T2)
8	Adhesive S of Termin		No indication of the terminal ele	of peeling shall occur on ectrode.	Pull force shall be applied for 10 ± 1 second. $\leq 06035N(= 0.5 \text{ Kg}\cdot\text{f})$ $> 060310N(= 1.0 \text{ Kg}\cdot\text{f})$ N·f
9		Appear- ance C-Meter	No mechanica Capacitance C Char. X7R	-	Bending shall be applied to the 1.0 mm with 1.0 mm/sec. The duration of the applied forces shall be $5 \pm 1 \sec$ Bending Limit $45 \pm 1 mm$





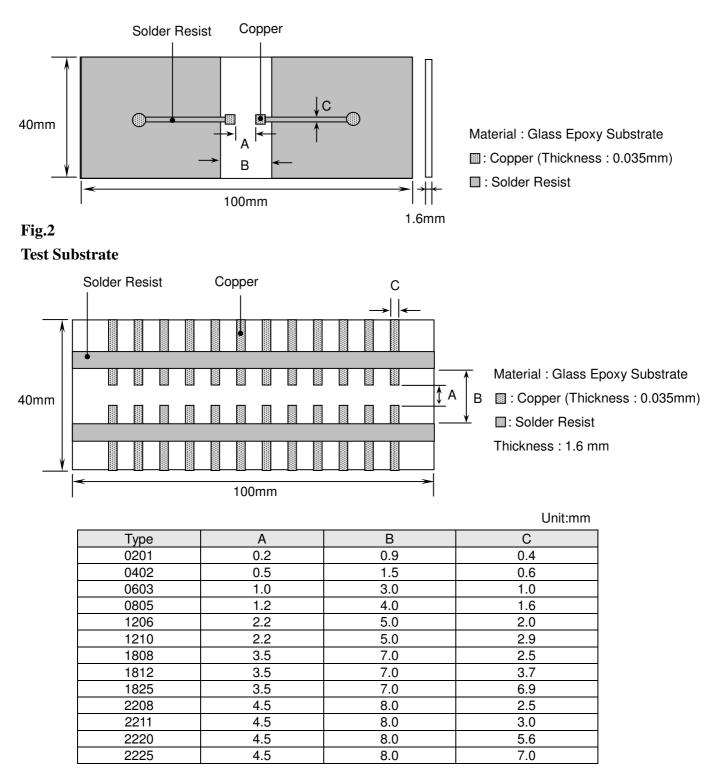
No.	lte	em	Spec	ification	Test Condition		
10	Solderability			the terminal surface ewly, so metal part t or dissolve .	Solder Temperature : $245\pm5^{\circ}$ CDip Time : 5 ± 0.5 sec.Immersing Speed : $25\pm10\%$ mm/sSolder : Lead Free SolderFlux :RosinPreheat : At 80~120 °C for 10~30sec.		
11	Resistance To Soldering Heat	Appear- ance Capacit- ance D.F. Class II Insulation Resistance Withstand Voltage	No mechanical dat Characteristic Class X7R II To satisfy the spec To satisfy the spec To satisfy the spec	Cap. Change Within ± 10% ified initial value	Class II capacitor shall be set for 48±4 hours a room temperature after one hour heat treatment at 150 +0/-10°C before initial measure. Preheat : At 150± 10°C For 60~120sec. Dip : Solder Temperature of 260± 5°C Dip Time : 10 ± 1sec. Immersing Speed : 25±10% mm/s Flux :Rosin Measure at room temperature after cooling for Class II : 48 ± 4 Hours		
12	Tempera ture Cycle	Appear- ance Capacit- ance D.F. Class II Insulation Resistance	No mechanical dar Characteristic Class X7R II To satisfy the spec	Cap. Change Within ± 7.5%	Class II capacitor shall be set for 48 ± 4 hours at room temperature after one hour heat treatment at 150 +0/-10 °C before initial measure. Capacitor shall be subjected to five cycles of the temperature cycle as following: Step Temp.(°C) Time(min) 1 Min Rated Temp. +0/-3 30 2 25 3 3 Max Rated Temp. +3/-0 30 4 25 3 Measure at room temperature after cooling for Class II :48 ± 4 Hrs Solder the capacitor on P.C. board shown in Fig 2. before testing.		
13	Humidity	Appear- ance Capacit- ance D.F. Class II Insulation Resistance	No mechanical dat Characteristic Class X7R II Char. X7R : 5.0% max. 50/C Ω min.	mage shall occur Cap. Change Within ± 15% Maximum	Class II capacitor shall be set for 48± 4 hours at room temperature after one hour heat treatment at 150+0/-10 °C before initial measure. Temperature : 40± 2°C Relative Humidity : 90 ~ 95%RH Test Time : 500 +12/-0Hr Measure at room temperature after cooling for Class II : 48 ± 4Hrs Solder the capacitor on P.C. board shown in Fig 2. before testing.		



No.	Ite	m		Specifi	ication	Test Condition	
14	High Temperature	Appear- ance	No mech	nanical da	mage shall occur	Class II capacitors applied DC voltage (following table) is applied for one hour at maximum	
	Load	Capacit-		cteristic	Cap. Change	operation temperature $\pm 3^\circ C$ then shall be set for	
	(Life Test)	ance	Class	X7R	Within ± 15%	48±4 hours at room temperature and the initial	
		D.F.	∏ Char		maximum	measurement shall be conducted.	
		D.r. Class ∏		.0% max.	maximum	Applied Voltage : 120%Rated Voltage	
		Insulation	50/CΩm			Test Time : 1000 +12/-0Hr	
		Resistance	00/01211			Current Applied : 50 mA Max.	
						Measure at room temperature after cooling for Class Π : 48 ± 4 Hours	
45	Vibration	Appear-	No mech	nanical da	mage shall occur	Solder the capacitor on P.C. Board shown in	
15	Vibration	ance		ianical ua	mage shan occur	Fig 2. before testing.	
		Capacit-	Chara	cteristic	Cap. Change		
		ance	Class	X7R	Within ± 7.5%	Vibrate the capacitor with amplitude of 1.5mm	
			П			P-P changing the frequencies from 10Hz to	
		D.F.	To satisf	y the spec	ified initial value	55Hz and back to 10Hz in about 1 min.	
		Class II	To soll (March 1 - 11 - 1	Repeat this for 2 hours each in 3perpendicular	
		Insulation Resistance	io satisf	y the spec	ified initial value	directions.	
		nesistance					



Fig.1 P.C. Board for Bending Strength Test



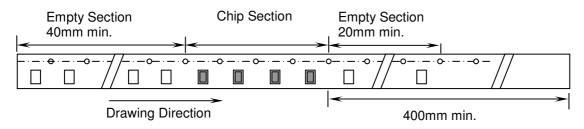


8. Packing

8.1 Bulk Packing

According to customer request.

8.2 Chip Capacitors Tape Packing



8.3 Material And Quantity

Tape	0201	0402	0603/	0805
Material	T≦0.39mm	T≦0.70mm	T≦1.00mm	T>1.00mm
Paper	15,000 pcs/Reel	10,000 pcs/Reel	4,000 pcs/Reel	NA
Plastic	NA	NA	NA	3,000 pcs/Reel

Tape	1206						
Material	$T \leq 1.00 mm$	1.00 mm $<$ T \leq 1.25 mm	T>1.25mm				
Paper	4,000 pcs/Reel	NA	NA				
Plastic	NA	3,000 pcs/Reel	2,000 pcs/Reel				

Tape	1808/1210						
Material	T≦1.25mm	1.25 mm $<$ T \leq 2.40mm	T>2.40mm				
Paper	NA	NA	NA				
Plastic	3,000 pcs/Reel	1,000/2,000 pcs/Reel	500/1,000 pcs/Reel				

Tape	1812/2211/2220		1825/2	2225	2208
Material	T≦2.20mm	T>2.20mm	T≦2.20mm	T>2.20mm	T≦2.20mm
Paper	NA	NA	NA	NA	NA
Plastic	1,000 pcs/Reel	700 pcs/Reel	700 pcs/Reel	400 pcs/Reel	1,000 pcs/Reel

NA : Not Available

HHEC

8.4 Cover Tape Reel Off Force

8.4.1 Peel-Off Force

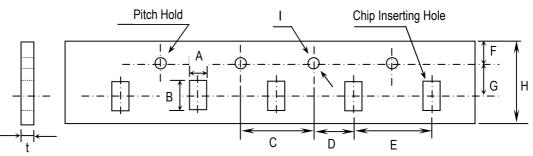
5 g·f \leq Peel-Off Force \leq 70 g·f

8.4.2 Measure Method





8.5 Paper Tape

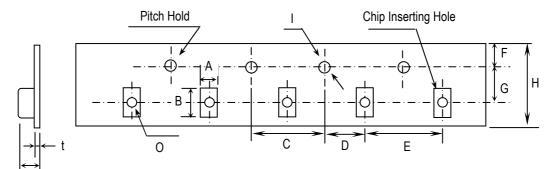


Unit:mm

TYPE	А	В	С	D	E
0201	0.37± 0.1	0.67± 0.1	4.00± 0.1	2.00± 0.05	2.00± 0.1
0402	0.61± 0.1	1.20± 0.1			
0603	1.10± 0.2	1.90± 0.2			4.00± 0.1
0805	1.50± 0.2	2.30± 0.2			
1206	1.90± 0.2	3.50± 0.2			
1210	2.90± 0.2	3.60± 0.2			

TYPE	F	G	Н	I	t
0201	1.75± 0.10	3.50± 0.05	8.0± 0.30	<i>φ</i> 1.50 +0.10/-0	1.10 max.
0402					
0603					
0805					
1206					
1210					

8.6 Plastic Tape



Unit:mm

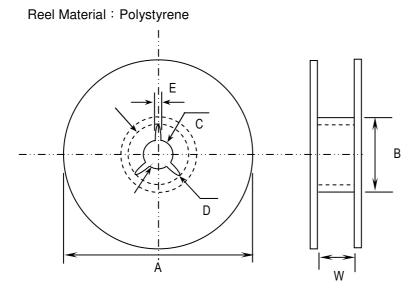
Туре	А	В	С	D	E	F
0805	1.5±0.2	2.3±0.2	4.0± 0.1	2.0 ± 0.05	4.0± 0.1	1.75± 0.1
1206	1.9±0.2	3.5±0.2				
1210	2.9±0.2	3.6±0.2				
1808	2.5±0.2	4.9±0.2				
1812	3.6±0.2	4.9±0.2			8.0± 0.1	
1825	6.9±0.2	4.9±0.2				
2208	2.5±0.2	6.1±0.2				
2211	3.2±0.2	6.1±0.2				
2220	5.4±0.2	6.1±0.2]			
2225	6.9±0.2	6.1±0.2				





Туре	G	Н	I	J	t	0
0805	3.5± 0.05	8.0± 0.3	<i>φ</i> 1.5+0.1/-0	3.0 max.	0.3 max.	1.0± 0.1
1206						
1210						
1808	5.5± 0.05	12.0 ± 0.3		4.0 max.		1.5± 0.1
1812						
1825						
2208						
2211						
2220						
2225						

8.7 Reel Dimensions



Unit:mm

Туре	A	В	С	D	E	W
0201	φ 382 max	arphi 50 min	arphi 13± 0.5	φ 21± 0.8	2.0±0.5	10± 0.15
0402						
0603						
0805						
1206						
1210						
1808	φ 178±2.0	arphi 60±2.0				13±0.3
1812						
1825						
2208						
2211						
2220						
2225						





Precautionary Notes:

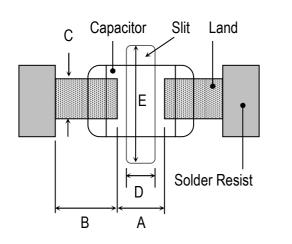
1. Storage

Store the capacitors where the temperature and relative humidity don't exceed 40 °C and 70%RH. We recommend that the capacitors be used within 12 months from the date of manufacturing. Store the products in the original package and do not open the outer wrapped, polyethylene bag, till just before usage. If it is open, seal it as soon as possible or keep it in a desiccant with a desiccation agent.

2. Construction of Board Pattern

Improper circuit layout and pad/land size may cause excessive or not enough solder amount on the PC board. Not enough solder may create weak joint, and excessive solder may increase the potential of mechanical or thermal cracks on the ceramic capacitor. Therefore we recommend the land size to be as shown in the following table:

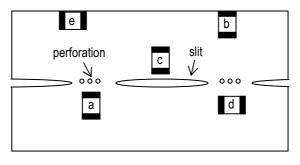
2.1 Size and recommend land dimensions for reflow soldering .



EIA Code	Chip (mm)			L	and (mm)		
EIA Coue	L	W	А	В	С	D	E
0201	0.60	0.30	0.2~0.3	0.2~0.4	0.2~0.4		
0402	1.00	0.50	0.3~0.5	0.3~0.5	0.4~0.6		
0603	1.60	0.80	0.4~0.6	0.6~0.7	0.6~0.8		
0805	2.00	1.25	0.7~0.9	0.6~0.8	0.8~1.1		
1206	3.20	1.60	2.2~2.4	0.8~0.9	1.0~1.4	1.0~2.0	3.2~3.7
1210	3.20	2.50	2.2~2.4	1.0~1.2	1.8~2.3	1.0~2.0	4.1~4.6
1808	4.60	2.00	2.8~3.4	1.8~2.0	1.5~1.8	1.0~2.8	3.6~4.1
1812	4.60	3.20	2.8~3.4	1.8~2.0	2.3~3.0	1.0~2.8	4.8~5.3
1825	4.60	6.35	2.8~3.4	1.8~2.0	5.1~5.8	1.0~4.0	7.1~8.3
2208	5.70	2.00	4.0~4.6	2.0~2.2	1.5~1.8	1.0~4.0	3.6~4.1
2211	5.70	2.80	4.0~4.6	2.0~2.2	2.0~2.6	1.0~4.0	4.4~4.9
2220	5.70	5.00	4.0~4.6	2.0~2.2	3.5~4.8	1.0~4.0	6.6~7.1
2225	5.70	6.35	4.0~4.6	2.0~2.2	5.1~5.8	1.0~4.0	7.1~8.3

2.2 Mechanical strength varies according to location of chip capacitors on the P.C. board. Design layout of components on the PC board such a way to minimize the stress imposed on the components, upon flexure of the boards in depanelization or other processes.

Component layout close to the edge of the board or the "depanelization line" is not recommended. Susceptibility to stress is in the order of: a>b>c and d>e







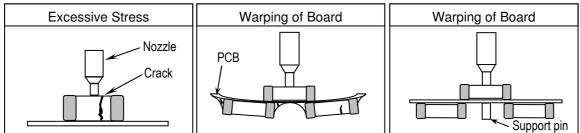
HVC-021-2005

2.3 Layout Recommendation

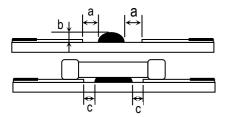
Example	Use of Common Solder Land	Solder With Chassis	Use of Common Solder Land With Other SMD
Need to Avoid	Lead Wire Chip Solder	Chassis \downarrow Excessive Solder \downarrow \downarrow \downarrow \downarrow \downarrow \downarrow \downarrow \downarrow \downarrow \downarrow	Solder Land
Recommendation	Lead Wire Chip Solder Resist Adhesive PCB Solder Land	Solder Resist	

3. Mounting

3.1 Sometimes crack is caused by the impact load due to suction nozzle in pick and place operation. In pick and place operation, if the low dead point is too low, excessive stress is applied to component. This may cause cracks in the ceramic capacitor, therefore it is required to move low dead point of a suction nozzle to the higher level to minimize the board warp age and stress on the components. Nozzle pressure is typically adjusted to 1N to 3N (static load) during the pick and place operation.



3.2 Amount of Adhesive



Example : 0805 & 1206

a	0.2mm min.	
b	70 ~ 100 μm	
С	Do not touch the solder land	



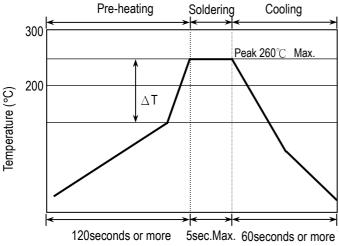


4. Soldering

4.1. Wave Soldering

Most of components are wave soldered with solder at Peak Temperature.. Adequate care must be taken to prevent the potential of thermal cracks on the ceramic capacitors. Refer to the soldering methods below for optimum soldering benefits.

Recommend flow soldering temperature Profile



Soldering Method	Peak Temp.($^{\circ}$ C) / Duration (sec)
1206/0805/0603	∆ T ≤ 100~150°C max.
Pb-Sn Solder	250°C (max.) / 3sec(max.)
Lead Free Solder	260°C (max.) / 5sec(max.)

Recommended solder compositions

Sn-37Pb (Pb - Sn Solder)

Sn-3.0Ag-0.5Cu (Lead Free Solder)

To optimize the result of soldering, proper preheating is essential:

- 1) Preheat temperature is too low
 - a. Flux flows to easily
 - b. Possibility of thermal cracks
- 2) Preheat temperature is too high
 - a. Flux deteriorates even when oxide film is removed
 - b. Causes warping of circuit board
 - c. Loss of reliability in chip and other components

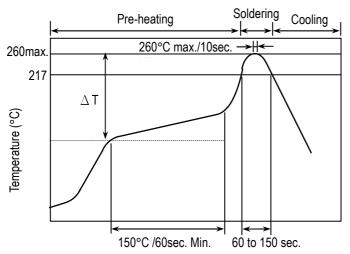
Cooling Condition:

Natural cooling using air is recommended. If the chips are dipped into a solvent for cleaning, the temperature difference (Δ T) between the solvent and the chips must be less than 100 °C.

4.2 Reflow Soldering

Preheat and gradual increase in temperature to the reflow temperature is recommended to decrease the potential of thermal crack on the components. The recommended heating rate depends on the size of component, however it should not exceed 3°C/Sec.

Recommend reflow profile for Lead-Free soldering temperature Profile (J-STD-020D)



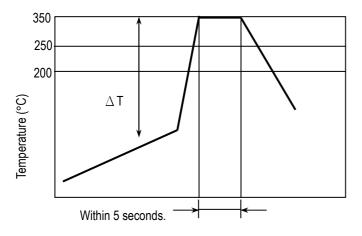
※ The cycles of soldering : Twice (max.)

Soldering Method	Change in Temp.(°C)
1206 and Under	$\Delta T \leq 190 \ ^{\circ}\mathrm{C}$
1210 and Over	∆ T ≦ 130 °C



4.3 Hand Soldering

Sudden temperature change in components, results in a temperature gradient recommended in the following table, and therefore may cause internal thermal cracks in the components. In general a hand soldering method is not recommended unless proper preheating and handling practices have been taken. Care must also be taken not to touch the ceramic body of the capacitor with the tip of solder Iron.



Soldering Method	Change in Temp.(°C)
1206 and Under	$\Delta T \leq 150 \ ^{\circ}C$
1210 and Over	Δ T \leq 130 $^\circ$ C

How to Solder Repair by Solder Iron

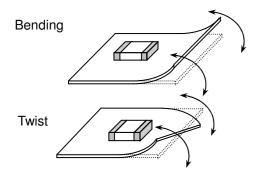
- 1) Selection of the soldering iron tip
 - The required temperature of solder iron for any type of repair depends on the type of the tip, the substrate material, and the solder land size.
- 2) recommended solder iron condition
 - a.) Preheating Condition : Board and components should be preheated sufficiently at 150 ℃ or over, and soldering should be conducted with soldering iron as boards and components are maintained at sufficient temperatures.
 - b.) Soldering iron power shall not exceed 30 W.
 - c.) Soldering iron tip diameter shall not exceed 3mm.
 - d.) Temperature of iron tip shall not exceed 350 °C., and the process should be finished within 5 seconds. (refer to MIL-STD-202G)
 - f.) Do not touch the ceramic body with the tip of solder iron. Direct contact of the soldering iron tip to ceramic body may cause thermal cracks.
 - g.) After soldering operation, let the products cool down gradually in the room temperature.

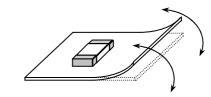
5. Handling after chip mounted

5.1 Proper handling is recommended, since excessive bending and twist of the board, depends on the orientation of the chip on the board, may induce mechanical stress and cause internal crack in the capacitor.

Higher potential of crack

Lower potential of crack





5.2 There is a potential of crack if board is warped due to excessive load by check pin

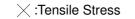


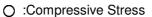


IHHEC is a trademark of Holy Stone Enterprise Co., Ltd



- 5.3 Mechanical stress due to warping and torsion.
 - (a) Crack occurrence ratio will be increased by manual separation.
 - (b) Crack occurrence ratio will be increased by tensile force , rather than compressive force.

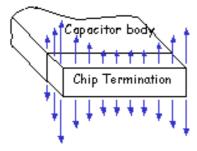


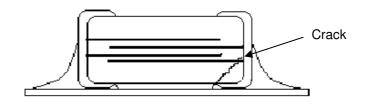






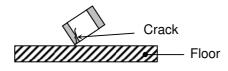
Capacitor Stress Analysis



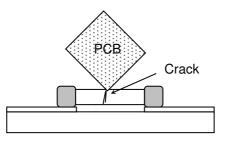


6. Handling of Loose Chip Capacitor

6.1 If dropped the chip capacitor may crack.



6.2 In piling and stacking of the P.C. boards after mounting for storage or handling, the corner of the P.C. board may hit the chip capacitor mounted on another board to cause crack.



7. Safekeeping condition and period

For safekeeping of the products, we recommend to keep the storage temperature between +5 to +40 $^{\circ}$ C and under humidity of 20 to 70% RH. The shelf life of capacitors is 12 months.



X-ON Electronics

Largest Supplier of Electrical and Electronic Components

Click to view similar products for Multilayer Ceramic Capacitors MLCC - SMD/SMT category:

Click to view products by IHHEC / Holy Stone manufacturer:

Other Similar products are found below :

M39014/02-1218V M39014/02-1225V M39014/22-0631 D55342E07B523DR-T/R NIN-FB391JTRF NIN-FC2R7JTRF NMC0402NPO220J50TRPF NMC0402X5R105K6.3TRPF NMC0402X5R224K6.3TRPF NMC0402X7R103J25TRPF NMC0402X7R153K16TRPF NMC0603NPO101F50TRPF NMC0603NPO1R8C50TRPF NMC0603NPO201J50TRPF NMC0603X5R475M6.3TRPF NMC0805NPO270J50TRPF NMC0805NPO681F50TRPF NMC0805NPO820J50TRPF NMC0805X7R224K16TRPLPF NMC0805X7R224K25TRPF NMC1206X7R102K50TRPF NMC1206X7R475K10TRPLPF NMC-Q0402NPO8R2D200TRPF C1206C101J1GAC C1608C0G2A221J C1608X7R1E334K C2012C0G2A472J 2220J2K00562KXT 1812J2K00332KXT CDR04BX104AKSR CDR31BX103AKWR CDR33BX104AKUR CDR33BX683AKUS CGA2B2C0G1H010C CGA2B2C0G1H040C CGA2B2C0G1H050C CGA2B2C0G1H060D CGA2B2C0G1H070D CGA2B2C0G1H120J CGA2B2C0G1H151J CGA2B2C0G1H1R5C CGA2B2C0G1H2R2C CGA2B2C0G1H390J CGA2B2C0G1H391J CGA2B2C0G1H3R3C CGA2B2C0G1H680J CGA2B2C0G1H688D CGA2B2C0G1H820J CGA2B2X8R1H152K CGA2B2X8R1H221K